

Abstracts

Active probes for 2-port network analysis within 70-230 GHz

O. Wohlgemuth, M.J.W. Rodwell, R. Reuter, J. Braunstein and M. Schlechtweg. "Active probes for 2-port network analysis within 70-230 GHz." 1999 MTT-S International Microwave Symposium Digest 99.4 (1999 Vol. IV [MWSYM]): 1635-1638 vol.4.

Active probes for 2-port on-wafer network analysis within 70-230 GHz are presented. The probe contains an integrated circuit, based on nonlinear transmission lines (NLTL), which has all elements of an S-parameter test set. 2-port measurements with these active probes were carried out. Compared to earlier active probe systems, measurement accuracy is greatly improved.

 [Return to main document.](#)